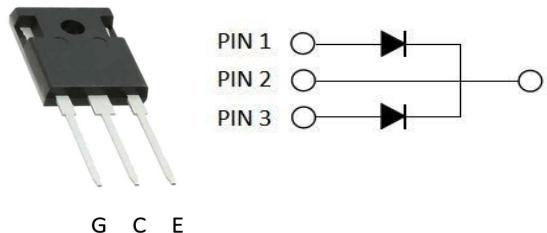


## Silicon Carbide Schottky Diode

### Product Summary

Parameter	Value	Unit
VRRM	650	V
IF	40	A
VF	1.45	V



Maximum Ratings ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
VRRM	Repetitive Peak Reverse Voltage	650	V		
VRSM	Surge Peak Reverse Voltage	650	V		
VDC	DC Blocking Voltage	650	V		
IF	Continuous Forward Current (Per Leg/Per Device)	20* 40* *	A	$T_c=150^\circ\text{C}$	Fig.7
IFRM	Repetitive Peak Forward Surge Current	140*	A	$T_c=25^\circ\text{C}, tp=10\text{ms}, \text{Half Sine Wave}$	
IRSM	Non-Repetitive Peak Forward Surge Current	170*	A	$T_c=25^\circ\text{C}, tp=10\text{ms}, \text{Half Sine Wave}$	
IF.Max	Non-Repetitive Peak Forward Surge Current	1360*	A	$T_c=25^\circ\text{C}, tp=10\mu\text{s}, \text{Pulse}$	
Ptot	Power Dissipation	159* 68*	W	$T_c=25^\circ\text{C} \quad T_c=110^\circ\text{C}$	Fig.6
Ty,Tstg	Operating Junction and Storage Temperature	-55 to +175	°C		

Note: \*Per Leg, \*\*Per Device

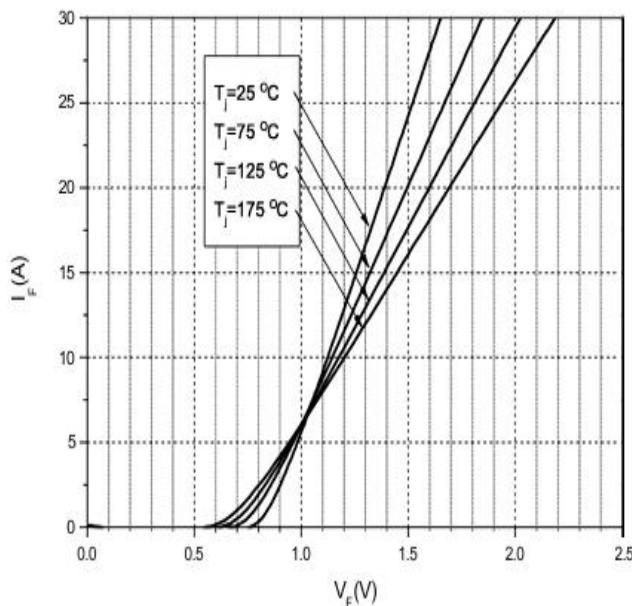
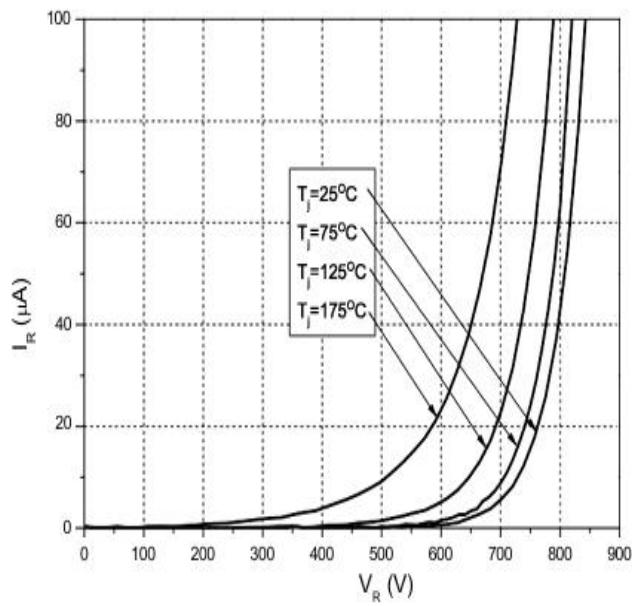
### Electrical Characteristics (Per Leg)

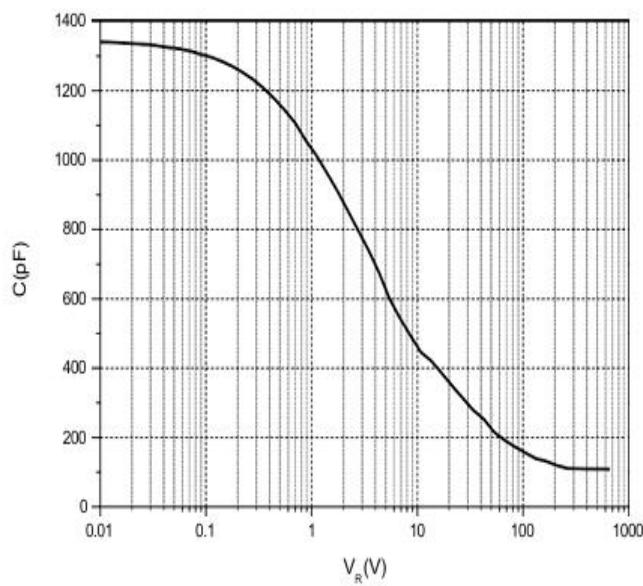
Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
VF	Forward Voltage	1.45 1.85	1.8 2.4	V	IF=20 A Tr=25°C IF=20A Tr=175°C	Fig.1
IR	Reverse Current	2 40	20 200	µA	VR=650V Tr=25°C VR=650V Tr=125°C	Fig.2
Qc	Total Capacitive Charge	65		nC	VR = 400 V, TJ = 25°C $Q_c = \int VR C V dV$	Fig.4

C	Total Capacitance	1340 120 109		pF	VR=0V,Tj=25°C,f=1 MHz VR=200V,Tr=25°C,f=1 MHz VR=400V,Tj=25°C,f=1 MHz	Fig.3
Ec	Capacitance Stored Energy	16		μJ	VR=400V	Fig.5

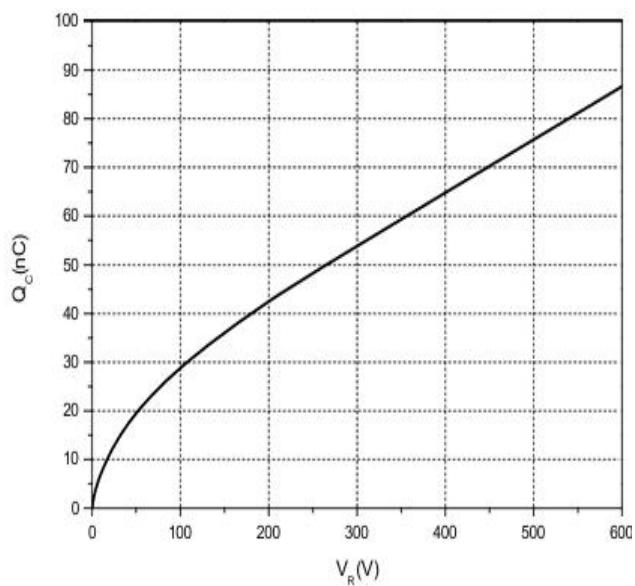
**Thermal Characteristics(Per Leg)**

Symbol	Parameter	Typ.	Unit	Note
Rarc	Thermal Resistance from Junction to Case	0.94	C/W	Fig.8

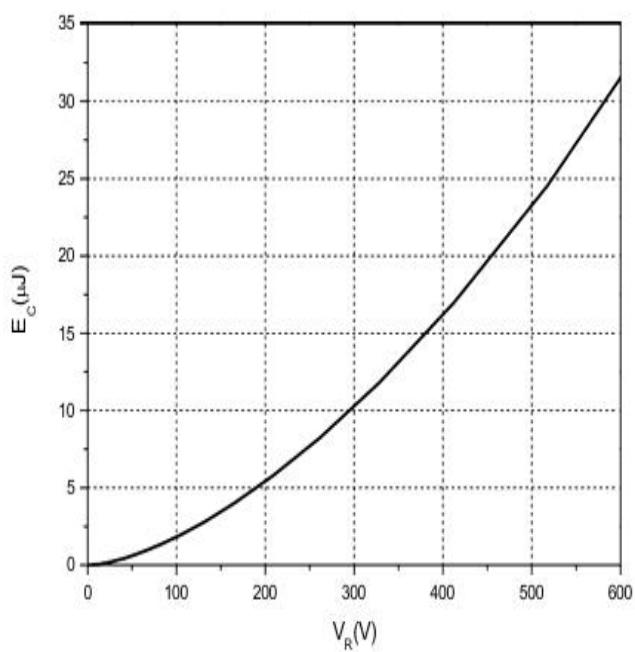
**Figure 1.Forward Characteristics**

**Figure 2.Reverse Characteristics**

**Figure 3.Capacitance vs.Reverse Voltage**  
**Voltage**
**Figure 4.Total Capacitance Charge vs.Reverse**



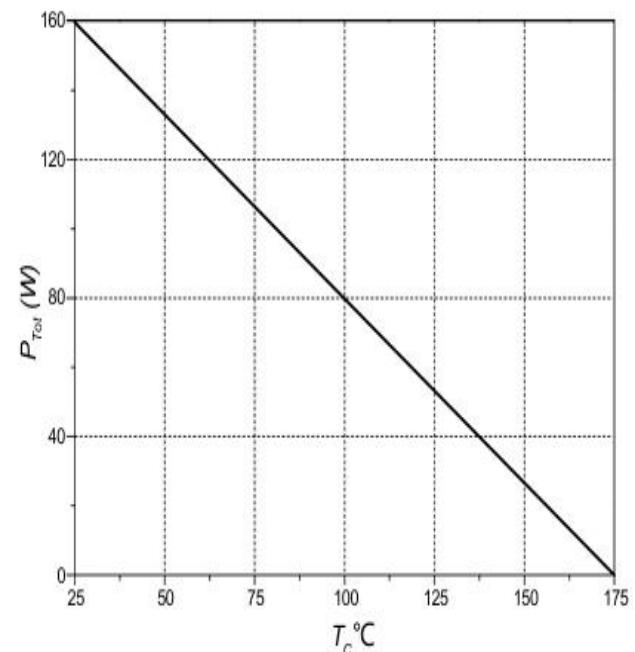
**Figure 5.Capacitance Stored Energy**



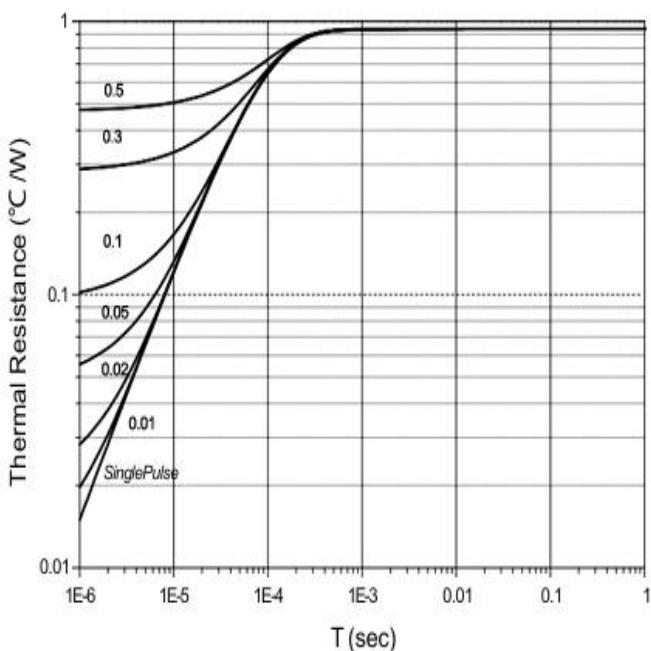
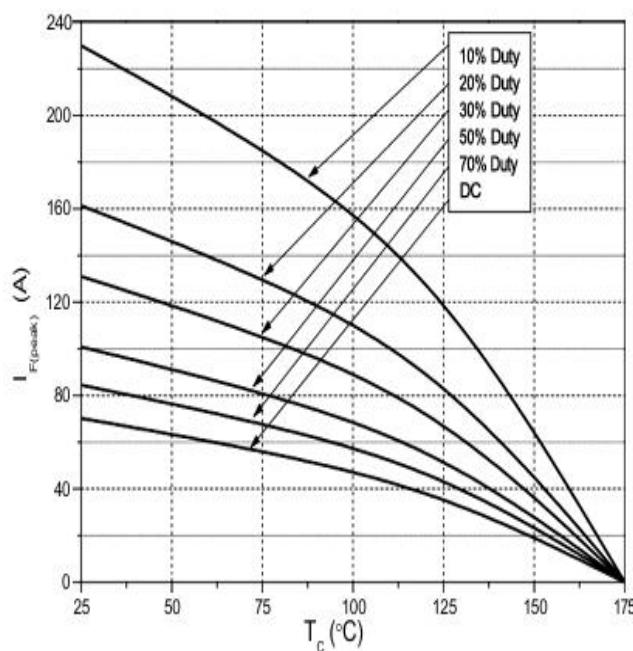
**Figure 6. Power Derating**



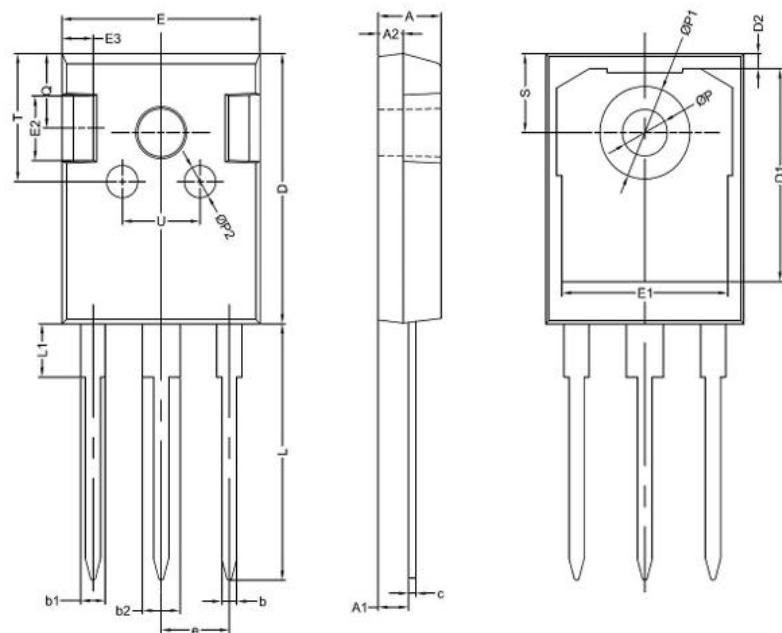
**Figure 7.Current Derating**



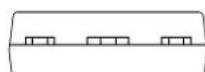
**Figure 8.Transient Thermal Impedance**



#### Package Dimensions:



符号	机械尺寸/mm		
	最小值	典型值	最大值
A	4.80	5.00	5.20
A1	2.21	2.41	2.61
A2	1.90	2.00	2.10
b	1.10	1.20	1.35
b1		2.00	
b2		3.00	
c	0.55	0.60	0.75
D	20.80	21.00	21.20
D1		16.55	
D2		1.20	
E	15.60	15.80	16.0
E1		13.30	
E2		5.00	
E3		2.50	
e	5.44		
L	19.42	19.92	20.42
L1		4.13	
P	3.50	3.60	3.70
P1	-	-	7.40
P2		2.50	
Q		5.80	
S	6.05	6.15	6.25
T		10.00	
U		6.20	



**TO-247-3L**

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